

**U.S. PATENT DOCUMENTS**

[illegible]

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION	
					YES	NO
MLT	JP9-199753	07/31/1997	Japan		X	

EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)	
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/Minh-Loan Tran/

02/04/2007

EXAMINER	Minh loan Tran	DATE CONSIDERED	2/04/07
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**EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449	APPLICATION NO. 10/502,110	CASE NO. 10555-085
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE July 21, 2004	ART UNIT 2826
APPLICANT(S): Ko, et al.		

## REFERENCE DESIGNATION

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EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)	
MLT		M.A. Itzler, C.S. Wang, S. McCoy, N. Codd and N. Komba, Planar bulk InP avalanche photodiode design for 2.5 and 10Gb/s applications, Proc 24th ECOC 1998, paper MoB03
MLT		L.E. Tarof, J. Yu, R. Bruce, D.G. Knight, T. Baird and B. Oosterbrink, High frequency performance of separate absorption grading charge and multiplication InP/InGaAs avalanche photodiodes, IEEE Photon. Technol. Lett. 5, 672-674, 1993
MLT		Watanabe, T. Nakata, M. Tsuji, K. Makita, K. Taguchi, High reliability and low dark current 10 Gb/s planar superlattice avalanche photodiodes, IEEE Photon. Technol. Lett. 9, 1619-1621, 1997
MLT		J.C. Campbell, S. Demiquel, F. Ma, A. Beck, X. Guo, S. Wang, X. Zeng, X. Li, J.D. Beck, M.A. Kinch, A. Huntington, L.A. Coldren, J. Decobert, N. Tschertner, Recent advances in avalanche photodiodes, IEEE J. Select. Topics Quantum Electron., 10, 777-787, 2004
MLT		R.R. Sutherland, C.P. Skrimshire, M.J. Robertson, A reliability methodology applied to very high reliability planar InGaAs/InP PIN photodetectors, Br. Telecom. Technol. J., 7, 69-77, Jan. 1989

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**LIST OF PATENTS AND PUBLICATIONS FOR  
APPLICANT'S INFORMATION DISCLOSURE  
STATEMENT**

FILING DATE	July 21, 2004
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ART UNIT	2826
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NAME \_\_\_\_\_

**CLASS/  
SUBCLASS**

**FILING  
DATE**

MLT

**5,126,281**

06/30/1992

Carey, et al.

**MLT**

**6,548,878B1**

04/15/2003

Nanleau, et al.

MLT

**6,794,631B2**

09/21/2004

Clark

**EXAMINER  
INITIAL**

**DOCUMENT  
NUMBER**

DATE \_\_\_\_\_

COUNTRY

**CLASS/  
SUBCLASS**

TRANSLATION	
YES	NO

**EXAMINER  
INITIAL**

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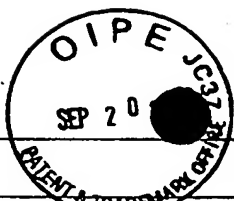
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
MLT	4,236,069	11/25/1980	Laughlin		
	4,597,004	06/24/1986	Longeway, et al.		
	4,686,550	08/11/1987	Capasso et al.		
	4,840,916	06/20/1989	Yasuda et al.		
	5,146,296	09/08/1992	Huth		
	5,179,430	01/12/1993	Torikai		
	5,365,077	11/15/1994	Metzger		
	5,539,221	07/23/1996	Tsuji et al.		
	5,552,629	09/03/1996	Watanabe		
	5,654,578	08/05/1997	Watanabe		
	5,818,096	10/06/1998	Ishibashi et al.		
	6,081,019	06/27/2000	White		
	6,107,652	08/22/2000	Scavennec et al.		
	6,229,161	05/08/2001	Nemati et al.		
	6,229,162	05/08/2001	Watanabe		
	6,326,650	12/04/2001	Allam		
MLT	6,359,322	03/19/2002	Haralson et al.		

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES NO
MLT	WO 03/065416	08/7/2003	Published App.		
MLT	WO 03/065417	08/7/2003	Published App.		
MLT	WO 03/065418	08/7/2003	Published App.		
			/		

EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)
MLT	Watanabe et al., IEEE Photonics Technology Letter 8, pp. 827-829, 1996

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MLT	2002/0070384	06/13/2002	Clark et al.	—	—
MLT	2003/0021322	01/30/2003	Steinle et al.	—	—

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